

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 129219		APPLICATION NO. 10/590,973	
INFORMATION DISCLOSURE STATEMENT							
(Use several sheets if necessary)							
				APPLICANT(S) Ali LAAYOUN et al.			
				FILING DATE August 28, 2006		GROUP 1626	
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EXAMINER					DATE CONSIDERED		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: December 31, 2009

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /M.B./

Sheet 2 of 2

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OTHER DOCUMENTS							
Examiner Initials	Cite No.	Including name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
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/Michael Barker/						01/04/2010	
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